

4/17/2013



**RELIABILITY MONITOR REPORT  
FOR**

**San Antonio 0.18 $\mu$ m Silicon Gate CMOS (S18)**

**MAXIM INTEGRATED**

**160 RIO ROBLES  
SAN JOSE, CA 95134**

**This Report was prepared by  
MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX17048	MAX77231EZL+	MAX77387EWP	MAX77693EWQ	MAX98400AET
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The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 16542      QUANTITY: 394      FAILS: 1      FITS: 6.9**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%      Ea: 0.7      Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2012 and 3/31/2013 .

**Process Information:**

Process Description: San Antonio 0.18µm Silicon Gate CMOS (S18)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1201	MAX98400AETX+	135°C	1000 HRS	70	0	TD7ZFY008B
HIGH TEMP OP LIFE	1214	MAX98400AETX+	135°C	1000 HRS	72	0	TD7ZFY014B
HIGH TEMP OP LIFE	1216	MAX77387EWP+	135°C	192 HRS	48	0	TAEU0Q001CQ
HIGH TEMP OP LIFE	1248	MAX77231EZL+T	135°C	240 HRS	80	1	TAKT1Q001AQ
HIGH TEMP OP LIFE	1302	MAX17048	125C, 5.0 VOLTS	192 HRS	77	0	ZJ386023ABB
HIGH TEMP OP LIFE	1303	MAX77693EWQ+T	135°C	192 HRS	47	0	TALC8A132AQ
<b>Total:</b>						<b>1</b>	

**STORAGE LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1201	MAX98400AETX+	150°C	1000 HRS	80	0	TD7ZFY008B
<b>Total:</b>						<b>0</b>	

**FAILURE RATE: MTTF (YRS): 16542      QUANTITY: 394      FAILS: 1      FITS: 6.9**